

		Results
9.	(((pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and parameter) and data) and input) and graphical [All Sources(- All Sciences -)]	1
8.	(((pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and parameter) and data) and input) and interface [All Sources(- All Sciences -)]	13
7.	(((pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and parameter) and data) and input [All Sources(- All Sciences -)]	41
6.	((pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and parameter) and data [All Sources(- All Sciences -)]	93
5.	(pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and parameter [All Sources(- All Sciences -)]	111
4.	(pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!)) and library [All Sources(- All Sciences -)]	4
3.	pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model!) [All Sources(- All Sciences -)]	198
2.	pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model) and FULL-TEXT(transistor) [All Sources(- All Sciences -)]	4
1.	pub-date > 1959 and pub-date < 2001 and FULL-TEXT(mismatch model) and FULL-TEXT(library) [All Sources(- All Sciences -)]	4

Copyright © 2004 Elsevier B.V. All rights reserved.  
ScienceDirect® is a registered trademark of Elsevier B.V.

**CiteSeer**Find: **Documents****Citations**Searching for **mismatch model and interface**.Restrict to: [Header](#) [Title](#) Order by: [Expected citations](#) [Hubs](#) [Usage](#) [Date](#) Try: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)3 documents found. **Order: number of citations.**

[The Suppression of Phonon induced Noise in Niobium.. - Poelaert Peacock Rando \(1996\) \(Correct\) \(1 citation\)](#)  
 follows similar work using an acoustic **mismatch model** [8,10,11] and is described in Appendix I. On  
 or are reflected at the substrate-junction **interface**, or reach the base film after too many  
 (table 2) for the substrate-buffer-Niobium **interface** cannot account for the dramatic attenuation of  
[astro.estec.esa.nl/pub/sciproj/poelaert\\_phonon1\\_JAP\\_01\\_03\\_96.ps.gz](http://astro.estec.esa.nl/pub/sciproj/poelaert_phonon1_JAP_01_03_96.ps.gz)

**One or more of the query terms is very common - only partial results have been returned. Try [Google \(CiteSeer\)](#).**

[Efficient support for IP over ATM - Hjalmtysson, Ramakrishnan \(Correct\)](#)  
 and avoids the complexities caused by service **model mismatch**. 1. Introduction Modern communication  
 it is becoming the de facto standard user network **interface**. The vast majority of new networking  
 of new networking applications assume this **interface**. Consequently, ATM technology is increasingly  
[www.research.att.com/~gisli/papers/GH98.ATM98ws.sent.ps](http://www.research.att.com/~gisli/papers/GH98.ATM98ws.sent.ps)

[Compilation, Synthesis, and Simulation of Hardware Description.. - Cheng \(1998\) \(Correct\)](#)  
 . 2 1.1.4 The **Model Mismatch** Problem .  
 .6 1.3.1 Stacks As A Universal Procedure **Interface** .7 1.3.2 Structured  
 7 1.3.1 Stacks As A Universal Procedure **Interface** The importance of this step is easy to  
[www-cad.eecs.berkeley.edu/~stcheng/pub/phd.ps.gz](http://www-cad.eecs.berkeley.edu/~stcheng/pub/phd.ps.gz)

Try your query at: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)CiteSeer.IST - Copyright [Penn State](#) and [NEC](#)

**CiteSeer**Find: [Documents](#)[Citations](#)Searching for **mismatch model and library**.Restrict to: [Header](#) [Title](#) Order by: [Expected citations](#) [Hubs](#) [Usage](#) [Date](#) Try: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)3 documents found. **Order: number of citations.**

[Embedding User Models in Intelligent Interfaces - Vadim Stefanuk Institute \(1997\) \(Correct\) \(2 citations\)](#)  
situation and the given state of the User **Model, Mismatch** Registration` is designed to discover the  
to the user. These services are taken from a **library** of available services. See [5] for a general  
attached procedures are used for this purpose. A **library** of such procedures (some of them are shown in  
[www.cs.uni-sb.de/UM97/VS/ps/StefanukV.ps](http://www.cs.uni-sb.de/UM97/VS/ps/StefanukV.ps)

**One or more of the query terms is very common - only partial results have been returned. Try [Google \(CiteSeer\)](#).**[Generating Information for Real-Time Optimization - Pfaff \(Correct\)](#)

97 C.2.2 Comparing RTO Systems When Plant/**Model Mismatch** is Present .106 D Statistical Significance  
University of Alberta **Library** Release Form Name of Author: George Charles  
is hereby granted to the University of Alberta **Library** to reproduce single copies of this thesis and to  
[www.ualberta.ca/dept/chemeng/control/reports/fraser/thesis\\_gpffaff.pdf](http://www.ualberta.ca/dept/chemeng/control/reports/fraser/thesis_gpffaff.pdf)

[Statistical Estimation with 1/f-Type Prior Models - Dufour \(Correct\)](#)

two issues with the use of the 1=f models: **model mismatch** and parameter estimation. We show that the  
Director, Graduate School Date Copy Deposited in **Library**: Reference Librarian Date Statistical  
[www.cdsp.neu.edu/info/students/rdufour/dufourMS.ps.gz](http://www.cdsp.neu.edu/info/students/rdufour/dufourMS.ps.gz)

Try your query at: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)CiteSeer.IST - Copyright [Penn State](#) and [NEC](#)

**CiteSeer**Find: [Documents](#)[Citations](#)Searching for **mismatch model and transistor**.Restrict to: [Header](#) [Title](#) Order by: [Expected citations](#) [Hubs](#) [Usage](#) [Date](#) Try: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)

7 documents found. Order: number of citations.

[Measurement and Modeling of MOS Transistor Current Mismatch in.. - Eric Felt \(1994\)](#) (Correct) (1 citation)  
 current mismatch and a new **transistor** current **mismatch model**. The new methodology is based on extracting  
 Measurement and Modeling of MOS **Transistor** Current Mismatch in Analog IC's Eric Felt Amit  
 presents a new methodology for measuring MOS **transistor** current mismatch and a new **transistor** current  
[ic.eecs.berkeley.edu/pub/Papers\\_Talks/Analog\\_Group/PostScript/ICCAD94\\_felt1.ps.Z](http://ic.eecs.berkeley.edu/pub/Papers_Talks/Analog_Group/PostScript/ICCAD94_felt1.ps.Z)

[Analog Integrated Circuits and Signal Processing.. - Systematic..](#) (Correct)  
 is considered, and a new ve parameters MOS **mismatch model** is introduced. The current mismatch between  
 Systematic Width-and-Length Dependent CMOS **Transistor** Mismatch Characterization and Simulation TERESA  
 for characterizing the random component of **transistor** mismatch in CMOS technologies. The methodology  
[www.imse.cnm.es/~bernabe/kl\\_dec99.pdf](http://www.imse.cnm.es/~bernabe/kl_dec99.pdf)

[An Asymptotically Constant, Linearly Bounded.. - Guardiani.. \(2000\)](#) (Correct)  
 parameters. Second, applying a device level **mismatch model** to the statistical simulation of electronic  
 and columns are ,representing parameter j for **transistor** i. The element represents the correlation  
 between different parameters on different **transistors** is also taken to be zero.i. e.for and .  
[www.sigda.org/Archives/ProceedingArchives/Dac/Dac2000/papers/2000/dac00/htmlfiles/sun\\_sgi/.../pdffiles/01\\_4.pdf](http://www.sigda.org/Archives/ProceedingArchives/Dac/Dac2000/papers/2000/dac00/htmlfiles/sun_sgi/.../pdffiles/01_4.pdf)

[Evaluation Of The Substrate Noise Effect On Analog.. - Zinzius, Lauwers.. \(2000\)](#) (Correct)  
 e#ect on the noise sensitivity. In addition a **mismatch model** was used #8#to see if device mismatch also  
 topology through the bulk e#ect of the MOS **transistors** #4#Three e#ects can easily be located. The  
 because they are already implemented in the **transistor** model #7#The body e#ect is in#uenced by the  
[www.imec.be/bandit/publications/ssmsd2000\\_Yann.pdf](http://www.imec.be/bandit/publications/ssmsd2000_Yann.pdf)

[A 5-Parameter Mismatch Model for Short Channel MOS.. -..](#) (Correct)  
 A 5-Parameter **Mismatch Model** for Short Channel MOS **Transistors**  
 5-Parameter **Mismatch Model** for Short Channel MOS **Transistors** TeresaSerrano-Gotarredona and Bernab  
 Abstract A new 5-parameter MOS **transistor mismatch model** is introduced capable of  
[www.imse.cnm.es/~bernabe/esscirc99.pdf](http://www.imse.cnm.es/~bernabe/esscirc99.pdf)

[A New Five-Parameter MOS Transistor Mismatch Model - Teresa Serrano-Gotarredona And](#) (Correct)  
 2000 37 A New Five-Parameter MOS **Transistor Mismatch Model** Teresa Serrano-Gotarredona and Bernab  
 NO. 1, JANUARY 2000 37 A New Five-Parameter MOS **Transistor Mismatch Model** Teresa Serrano-Gotarredona and  
 Abstract-A new five-parameter MOS **transistor mismatch model** is introduced capable of  
[www.imse.cnm.es/~bernabe/edl\\_jan00.pdf](http://www.imse.cnm.es/~bernabe/edl_jan00.pdf)

[MOS Transistor Mismatch for High Accuracy Applications - Van der Plas..](#) (Correct)  
 proportional to the mismatch (Pelgrom **mismatch model**)related through a technology constant. Also  
 MOS **Transistor** Mismatch for High Accuracy Applications G. Van  
 In this paper the matching behaviour of MOS **transistors** is analyzed for the realization of an  
[www.stw.nl/prorisc/prorisc99/proceedings/van\\_der\\_plas.pdf](http://www.stw.nl/prorisc/prorisc99/proceedings/van_der_plas.pdf)

Try your query at: [Google \(CiteSeer\)](#) [Google \(Web\)](#) [CSB](#) [DBLP](#)CiteSeer.IST - Copyright [Penn State](#) and [NEC](#)

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership | Publications/Services | Standards | Conferences | Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.8

 Welcome  
 United States Patent and Trademark Office


**IEEE Xplore®**  
 1 Million Documents  
 1 Million Users  
**...And Growing**  
 » Search Results

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **20** of **1091947** documents.  
 A maximum of **500** results are displayed, **50** to a page, sorted by **Publication year** in **Descending** order.

**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

mismatch model

Search

☐ Check to search within this result set
**Results Key:**
**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard
**1 A new five-parameter MOS transistor mismatch model**

*Serrano-Gotarredona, T.; Linares-Barranco, B.;*  
 Electron Device Letters, IEEE , Volume: 21 , Issue: 1 , Jan. 2000  
 Pages:37 - 39

[\[Abstract\]](#)   [\[PDF Full-Text \(104 KB\)\]](#)   IEEE JNL
**2 Disturbance and nonlinear Luenberger observers for estimating mechanical variables in permanent magnet synchronous motors under mechanical parameters uncertainties**

*Solsona, J.A.; Valla, M.I.;*  
 Industrial Electronics, 2000. ISIE 2000. Proceedings of the 2000 IEEE International Symposium on , Volume: 2 , 4-8 Dec. 2000  
 Pages:407 - 412 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(340 KB\)\]](#)   IEEE CNF
**3 A new strong inversion 5-parameter transistor mismatch model**

*Serrano-Gotarredona, T.; Linares-Barranco, B.;*  
 Circuits and Systems, 2000. Proceedings. ISCAS 2000 Geneva. The 2000 IEEE International Symposium on , Volume: 4 , 28-31 May 2000  
 Pages:381 - 384 vol.4

[\[Abstract\]](#)   [\[PDF Full-Text \(308 KB\)\]](#)   IEEE CNF
**4 A physical approach to mismatch modelling and parameter correlations**

*Oelun, J.; Grunebaum, U.; Schumacher, K.;*  
 Circuits and Systems, 2000. Proceedings. ISCAS 2000 Geneva. The 2000 IEEE International Symposium on , Volume: 4 , 28-31 May 2000  
 Pages:377 - 380 vol.4

[\[Abstract\]](#)   [\[PDF Full-Text \(328 KB\)\]](#)   IEEE CNF
**5 Parasitic and mismatch modeling for optimal stack generation [in CMOS]**

*Xuan Zeng; Mingyuan Li; Wenqing Zhao; Pushan Tang; Dian Zhou;*  
 Circuits and Systems, 2000. Proceedings. ISCAS 2000 Geneva. The 2000 IEEE International Symposium on , Volume: 3 , 28-31 May 2000  
 Pages:193 - 196 vol.3

[\[Abstract\]](#)   [\[PDF Full-Text \(328 KB\)\]](#)   IEEE CNF

**6 A comprehensive MOSFET mismatch model***Drennan, P.G.; McAndrew, C.C.;*

Electron Devices Meeting, 1999. IEDM Technical Digest. International , 5-8 Dec. 1999

Pages:167 - 170

[\[Abstract\]](#) [\[PDF Full-Text \(264 KB\)\]](#) IEEE CNF**7 A new 5-parameter MOS transistors mismatch model***Serrano-Gotarredona, T.; Linares-Barranco, B.;*

Electronics, Circuits and Systems, 1999. Proceedings of ICECS '99. The 6th IEEE International Conference on , Volume: 1 , 5-8 Sept. 1999

Pages:315 - 318 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(236 KB\)\]](#) IEEE CNF**8 Mismatch effects explained by the spectral model [MOS devices]***Oehm, J.; Grunebaum, U.; Schumacher, K.;*

Electronics, Circuits and Systems, 1999. Proceedings of ICECS '99. The 6th IEEE International Conference on , Volume: 2 , 5-8 Sept. 1999

Pages:1055 - 1058 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(336 KB\)\]](#) IEEE CNF**9 Diffused resistor mismatch modeling and characterization***Drennan, P.G.;*

Bipolar/BiCMOS Circuits and Technology Meeting, 1999. Proceedings of the 1999 , 26-28 Sept. 1999

Pages:27 - 30

[\[Abstract\]](#) [\[PDF Full-Text \(300 KB\)\]](#) IEEE CNF**10 A comprehensive vertical BJT mismatch model***Drennan, P.G.; McAndrew, C.C.; Bates, J.;*

Bipolar/BiCMOS Circuits and Technology Meeting, 1998. Proceedings of the 1998 , 27-29 Sept. 1998

Pages:83 - 86

[\[Abstract\]](#) [\[PDF Full-Text \(320 KB\)\]](#) IEEE CNF**11 A CMOS mismatch model and scaling effects***Shyh-Chyi Wong; Kuo-Hua Pan; Dye-Jyun Ma;*

Electron Device Letters, IEEE , Volume: 18 , Issue: 6 , June 1997

Pages:261 - 263

[\[Abstract\]](#) [\[PDF Full-Text \(140 KB\)\]](#) IEEE JNL**12 Mismatched finite-complexity MMSE decision feedback equalizers***Al-Dhahir, N.; Cioffi, J.M.;*

Signal Processing, IEEE Transactions on [see also Acoustics, Speech, and Signal Processing, IEEE Transactions on] , Volume: 45 , Issue: 4 , April 1997

Pages:935 - 944

[\[Abstract\]](#) [\[PDF Full-Text \(464 KB\)\]](#) IEEE JNL**13 Mismatch distance term compensation in centroid configurations with nonzero-area devices***Karhunen, E.S.; Fernandez, F.V.; Vazquez, A.R.;*

Circuits and Systems, 1997. ISCAS '97., Proceedings of 1997 IEEE International Symposium on , Volume: 3 , 9-12 June 1997

Pages:1644 - 1647 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) IEEE CNF**14 Mismatch modeling and characterization of bipolar transistors for statistical CAD***Hing-Yan To; Ismail, M.;*

Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on [see also Circuits and Systems I: Regular Papers, IEEE Transactions on] , Volume: 43 , Issue: 7 , July 1996

Pages:608 - 610

[\[Abstract\]](#) [\[PDF Full-Text \(440 KB\)\]](#) IEEE JNL

---

**15 Optimizing the match in weakly inverted MOSFET's by gated lateral bipolar action**

*Ming-Jer Chen; Jih-Shin Ho; Dang-Yang Chang;*

Electron Devices, IEEE Transactions on , Volume: 43 , Issue: 5 , May 1996

Pages:766 - 773

[\[Abstract\]](#) [\[PDF Full-Text \(828 KB\)\]](#) IEEE JNL

---

**16 Applying a submicron mismatch model to practical IC design**

*Guardiani, C.; Tomasini, A.; Benkoski, J.; Quarantelli, M.; Gubian, P.;*

Custom Integrated Circuits Conference, 1994., Proceedings of the IEEE 1994 , 1-4 May 1994

Pages:297 - 300

[\[Abstract\]](#) [\[PDF Full-Text \(260 KB\)\]](#) IEEE CNF

---

**17 Uncertainty modeling for ocean tomography systems**

*Rendas, M.J.D.; Bienvenu, G.; Moura, J.M.F.;*

OCEANS '93. 'Engineering in Harmony with Ocean'. Proceedings , 18-21 Oct. 1993

Pages:III108 - III111 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(348 KB\)\]](#) IEEE CNF

---

**18 Interface support of fault diagnosis strategies: a user-driven approach**

*van der Schaaf, T.W.; Brinkman, J.A.;*

Systems, Man and Cybernetics, 1993. 'Systems Engineering in the Service of Humans', Conference Proceedings., International Conference on , 17-20 Oct. 1993

Pages:364 - 368 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) IEEE CNF

---

**19 The moments of matched and mismatched hidden Markov models**

*Streit, R.L.;*

Acoustics, Speech, and Signal Processing [see also IEEE Transactions on Signal Processing], IEEE Transactions on , Volume: 38 , Issue: 4 , April 1990

Pages:610 - 622

[\[Abstract\]](#) [\[PDF Full-Text \(1008 KB\)\]](#) IEEE JNL

---

**20 VSS-type self-tuning control of direct-drive motor**

*Furuta, K.; Kosuge, K.; Kobayashi, K.;*

Industrial Electronics Society, 1989. IECON '89., 15th Annual Conference of IEEE , 6-10 Nov. 1989

Pages:281 - 286 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(276 KB\)\]](#) IEEE CNF

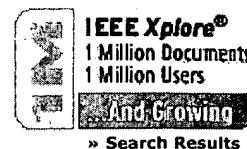
---

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.8

 Welcome  
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

## Full-text Search Prototype Results

[Feedback](#) [Help](#)
Your search matched **11** of **1043426** documents.A maximum of **500** results are displayed, **50** to a page, sorted by **Publication year** in **Descending** order.

## Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

mismatch model&lt;and&gt;interface

Search

☐ Check to search within this result set

## Results Key:

**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard

## 1 On adaptive decision rules and decision parameter adaptation for automatic speech recognition

Chin-Hui Lee; Qiang Huo;

Proceedings of the IEEE, Volume: 88, Issue: 8, Aug. 2000

Pages:1241 - 1269

[\[Abstract\]](#) [\[PDF Full-Text \(536 KB\)\]](#) IEEE JNL

## 2 Subject Index

Electron Device Letters, IEEE, Volume: 21, Issue: 12, Dec. 2000

Pages:627 - 647

[\[Abstract\]](#) [\[PDF Full-Text \(188 KB\)\]](#) IEEE JNL

## 3 Author Index

Electron Device Letters, IEEE, Volume: 21, Issue: 12, Dec. 2000

Pages:617 - 627

[\[Abstract\]](#) [\[PDF Full-Text \(124 KB\)\]](#) IEEE JNL

## 4 Large-vocabulary continuous speech recognition: advances and applications

Gauvain, J.-L.; Lamel, L.;

Proceedings of the IEEE, Volume: 88, Issue: 8, Aug. 2000

Pages:1181 - 1200

[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) IEEE JNL

## 5 Analysis of the impact of process variations on clock skew

Zanella, S.; Nardi, A.; Neviani, A.; Quarantelli, M.; Saxena, S.; Guardiani, C.;

Semiconductor Manufacturing, IEEE Transactions on, Volume: 13, Issue: 4, Nov. 2000

Pages:401 - 407

[\[Abstract\]](#) [\[PDF Full-Text \(104 KB\)\]](#) IEEE JNL

## 6 A novel adaptive mismatch cancellation system for quadrature IF radio receivers



*Li Yu; Snelgrove, W.M.;*

Circuits and Systems II: Analog and Digital Signal Processing, IEEE Transactions on [see also Circuits and Systems II: Express Briefs, IEEE Transactions on] , Volume: 46 , Issue: 6 , June 1999  
Pages:789 - 801

[\[Abstract\]](#) [\[PDF Full-Text \(328 KB\)\]](#) IEEE JNL

---

**7 HMM-based stressed speech modeling with application to improved synthesis and recognition of isolated speech under stress**

*Bou-Ghazale, S.E.; Hansen, J.H.L.;*

Speech and Audio Processing, IEEE Transactions on , Volume: 6 , Issue: 3 , May 1998  
Pages:201 - 216

[\[Abstract\]](#) [\[PDF Full-Text \(348 KB\)\]](#) IEEE JNL

---

**8 Modeling statistical dopant fluctuations in MOS transistors**

*Stolk, P.A.; Widdershoven, F.P.; Klaassen, D.B.M.;*

Electron Devices, IEEE Transactions on , Volume: 45 , Issue: 9 , Sept. 1998  
Pages:1960 - 1971

[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) IEEE JNL

---

**9 1997 Index**

Electron Device Letters, IEEE , Volume: 18 , Issue: 12 , Dec. 1997  
Pages:628 - 655

[\[Abstract\]](#) [\[PDF Full-Text \(1164 KB\)\]](#) IEEE JNL

---

**10 Interface support of fault diagnosis strategies: a user-driven approach**

*van der Schaaf, T.W.; Brinkman, J.A.;*

Systems, Man and Cybernetics, 1993. 'Systems Engineering in the Service of Humans', Conference Proceedings., International Conference on , 17-20 Oct. 1993  
Pages:364 - 368 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) IEEE CNF

---


**11 Characterisation and modeling of mismatch in MOS transistors for precision analog design**

*Lakshmikumar, K.R.; Hadaway, R.A.; Copeland, M.A.;*

Solid-State Circuits, IEEE Journal of , Volume: 21 , Issue: 6 , Dec 1986  
Pages:1057 - 1066

[\[Abstract\]](#) [\[PDF Full-Text \(1744 KB\)\]](#) IEEE JNL

---



# PORTAL

US Patent & Trademark Office

Search: ☐ The ACM Digital Library ☐ The Guide

**SEARCH**


Feedback Report a problem Satisfaction survey


Published before October 2000  
Terms used mismatch model

Found 6 of 106,862

Sort results by **relevance**

Display results **expanded form**

 [Save results to a Binder](#)

 [Search Tips](#)

☐ [Open results in a new window](#)

[Try an Advanced Search](#)  
[Try this search in The ACM Guide](#)

Results 1 - 6 of 6

Relevance scale ☐ ☐ ☐ ☐ ☐

### <sup>1</sup> [Measurement and modeling of MOS transistor current mismatch in analog IC's](#)

Eric Felt, Amit Narayan, Alberto Sangiovanni-Vincentelli

November 1994

**Proceedings of the 1994 IEEE/ACM international conference on Computer-aided design**

Full text available:  pdf(662.51 KB)

Additional information: [full citation](#), [abstract](#), [references](#), [citing](#), [index terms](#)

This paper presents a new methodology for measuring MOS transistor current mismatch and a new transistor current mismatch model. The new methodology is based on extracting the mismatch information from a fully functional circuit rather than on probing individual devices; this extraction leads to more efficient and more accurate mismatch measurement. The new model characterizes the total mismatch as a sum of two components, one systematic and the other random. For our process, we attribute n ...

### <sup>2</sup> [Working out usability: Linking surface error characteristics to root problems in user-based evaluation studies](#)

Mark Springett

May 1998

**Proceedings of the working conference on Advanced visual interfaces**

Full text available:  pdf(1.49 MB)

Additional information: [full citation](#), [abstract](#), [references](#)

This paper reports a study of novice subjects using Word 5.1. for the Macintosh. In particular, user errors were analysed. The intention was to investigate the difficulty, that evaluators have in determining root error causes from surface characteristics. Errors made by subjects were examined and classified in phenotype and genotype categories[3]. An error was classified in a genotype category if it was felt that system had failed to support that particular user mental action. The utility of the ...

**Keywords:** action cycle, error studies, phenotypes/genotypes

### <sup>3</sup> [Systematic design of a 14-bit 150-MS/s CMOS current-steering D/A converter](#)

G. Van der Plas, J. Vandenbussche, W. Daems, A. Van den Bosch, G. Gielen, W. Sansen

June 2000

**Proceedings of the 37th conference on Design automation**

Full text available:  pdf(1.95 MB)

Additional information: [full citation](#), [abstract](#), [references](#), [index terms](#)

This paper presents a D/A converter with a 14-bit intrinsic linearity in 0.5µm CMOS technology, which has been designed using a systematic design methodology for current-steering D/A converters. A flexible architecture is proposed for which the design parameters are calculated using a performance-driven top-down design methodology. The layout of the regular structure typical for D/A converters is automatically generated. Measurement results are reported. Due to the systematic design m ...

### <sup>4</sup> [Hierarchical statistical characterization of mixed-signal circuits using behavioral modeling](#)

Eric Felt, Stefano Zanella, Carlo Guardiani, Alberto Sangiovanni-Vincentelli

January 1997

**Proceedings of the 1996 IEEE/ACM international conference on Computer-aided design**

Full text available:

 pdf(231.06 KB)  [Publisher Site](#)

Additional information: [full citation](#), [abstract](#), [references](#), [citing](#), [index terms](#)

A methodology for hierarchical statistical circuit characterization which does not rely upon circuit-level Monte Carlo simulation is presented. The methodology uses principal component analysis, response surface methodology, and statistics to directly calculate the statistical distributions of higher-level parameters from the distributions of lower-level parameters. We have used the methodology to characterize a folded cascode operational amplifier and a phase-locked loop. This methodology permi ...

**Keywords:** statistical characterization, mixed-signal circuits, behavioral modeling

<sup>5</sup> [Synthesis of manufacturable analog circuits](#)

Tamal Mukherjee, L. R. Carley, R. A. Rutenbar

November 1994

**Proceedings of the 1994 IEEE/ACM international conference on Computer-aided design**

Full text available:  pdf(987.35.KB)

Additional information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)

We describe a synthesis system that takes operating range constraints and inter- and intra-circuit parametric manufacturing variations into account while designing a sized and biased analog circuit. Previous approaches to CAD for analog circuit synthesis have concentrated on nominal analog circuit design, and subsequent optimization of these circuits for statistical fluctuations and operating point ranges. Our approach simultaneously synthesizes and optimizes for operating and manufacturing ...

<sup>6</sup> [Confidence intervals for univariate discrete-event simulation output using the Kalman filter](#)

Randall B. Howard, Mark A. Gallagher, Kenneth W. Bauer, Peter S. Maybeck

December 1992

**Proceedings of the 24th conference on Winter simulation**

Full text available:  pdf(737.83.KB)

Additional information: [full citation](#), [references](#), [citations](#), [index terms](#)

Results 1 - 6 of 6

The ACM Portal is published by the Association for Computing Machinery. Copyright © 2004 ACM, Inc.

[Terms of Usage](#) [Privacy Policy](#) [Code of Ethics](#) [Contact Us](#)

Useful downloads:  Adobe Acrobat  QuickTime  Windows Media Player  Real Player